

<b>Notice of References Cited</b>	Application/Control No. 09/833,257	Applicant(s)/Patent Under Reexamination BUCHANAN ET AL.	
	Examiner Brian S Kwon	Art Unit 1614	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,141,958	08-1992	Crozier-Willi et al.	514/558
	B	US-5,043,328	08-1991	Weithmann, Klaus U.	514/78
	C	US-6,160,141	12-2000	Seidel, Michael C.	554/126
	D	US-4,871,768	10-1989	Bistrrian et al.	514/547
	E	US-5,015,483	05-1991	Haynes et al.	426/73
	F	US-5,223,285	06-1993	DeMichele et al.	426/72
	G	US-5,023,100	06-1991	Chang et al.	426/601
	H	US-5,567,730	10-1996	Miyashita et al.	514/549
	I	US-5,434,183	07-1995	Larsson-Backstrom, Carin	514/549
	J	US-5,502,077	03-1996	Breivik et al.	514/560
	K	US-6,077,525	06-2000	Vanderhoek, Jack Y.	424/442
	L	US-4,526,902	07-1985	Rubin, David	514/560
	M	US-6,710,032	03-2004	Teter et al.	514/23

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 60237017 A	11-1985	Japan	WAKABAYASHI et al.	A61K 09/10
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.